

Section 22 Electrical Characteristics

22.1 Absolute Maximum Ratings

Table 22-1 lists the absolute maximum ratings.

Table 22-1 Absolute Maximum Ratings

Item	Symbol	Value	Unit
Power supply voltage	V_{CC}	-0.3 to +7.0	V
Input voltage (except port 4)	V_{in}	-0.3 to $V_{CC} + 0.3$	V
Input voltage (port 4)	V_{in}	-0.3 to $AV_{CC} + 0.3$	V
Reference voltage	V_{ref}	-0.3 to $AV_{CC} + 0.3$	V
Analog power supply voltage	AV_{CC}	-0.3 to +7.0	V
Analog input voltage	V_{AN}	-0.3 to $AV_{CC} + 0.3$	V
Operating temperature	T_{opr}	Regular specifications: -20 to +75	°C
		Wide-range specifications: -40 to +85	°C
Storage temperature	T_{stg}	-55 to +125	°C

Caution: Permanent damage to the chip may result if absolute maximum rating are exceeded.

22.2 DC Characteristics

Table 22-2 lists the DC characteristics. Table 22-3 lists the permissible output currents.

Table 22-2 DC Characteristics

— Preliminary —

Conditions: $V_{CC} = AV_{CC} = 5.0 \text{ V} \pm 10\%$, $V_{ref} = 4.5 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V} \pm 1\%$, $T_a = -20 \text{ to } +75^\circ\text{C}$ (regular specifications), $T_a = -40 \text{ to } +85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Min	Typ	Max	Unit	Test Conditions	
Schmitt trigger input voltage	Port 2, P6 ₄ to P6 ₇ , PA ₄ to PA ₇	V_T^-	1.0	—	—	V	
		V_T^+	—	—	$V_{CC} \times 0.7$	V	
		$V_T^+ - V_T^-$	0.4	—	—	V	
Input high voltage	RES, STBY, NMI, MD ₂ to MD ₀	V_{IH}	$V_{CC} \times 0.7$	—	$V_{CC} + 0.3$	V	
	EXTAL		$V_{CC} \times 0.7$	—	$V_{CC} + 0.3$	V	
	Port1,3,5, B to G, P6 ₀ to P6 ₃ , PA ₀ to PA ₃		2.0	—	$V_{CC} + 0.3$	V	
	Port4		2.0	—	$AV_{CC} + 0.3$	V	
Input low voltage	RES, STBY, MD ₂ to MD ₀	V_{IL}	-0.3	—	0.5	V	
	NMI, EXTAL, Port1,3 to 5, B to G, P6 ₀ to P6 ₃ , PA ₀ to PA ₃		-0.3	—	0.8	V	
Output high voltage	All output pins	V_{OH}	$V_{CC} - 0.5$	—	—	V	$I_{OH} = -200 \mu\text{A}$
			3.5	—	—	V	$I_{OH} = -1 \text{ mA}$
Output low voltage	All output pins	V_{OL}	—	—	0.4	V	$I_{OL} = 1.6 \text{ mA}$
			Port1, A to C	—	—	1.0	V
Input leakage current	STBY, RES, NMI, MD ₂ to MD ₀	I_{in}	—	—	1.0	μA	$V_{in} = 0.5 \text{ to } V_{CC} - 0.5 \text{ V}$
	Port4		—	—	1.0	μA	$V_{in} = 0.5 \text{ to } AV_{CC} - 0.5 \text{ V}$

Note: 1. IF the A/D converter is not used, do not leave the AV_{CC} , AV_{SS} , and V_{ref} pins open. Connect AV_{CC} and V_{ref} to V_{CC} , and connect AV_{SS} to V_{SS} .

Table 22-2 DC Characteristics (cont)

– Preliminary –

Conditions: $V_{CC} = AV_{CC} = 5.0 \text{ V} \pm 10\%$, $V_{ref} = 4.5 \text{ V}$ to AV_{CC} , $V_{SS} = AV_{SS} = 0 \text{ V}^{*1}$, $T_a = -20$ to $+75^\circ\text{C}$ (regular specifications), $T_a = -40$ to $+85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Three-state leakage current (off state)	Port1 to 3, 5, 6, A to G $ I_{TSI} $	—	—	1.0	μA	$V_{in} = 0.5$ to $V_{CC} - 0.5 \text{ V}$
Input pull-up current	Port A to E $-I_p$	50	—	300	μA	$V_{in} = 0 \text{ V}$
Input capacitance	NMI C_{IN}	—	—	50	pF	$V_{in} = 0 \text{ V}$
	All input pins except NMI	—	—	15	pF	$f = 1 \text{ MHz}$ $T_a = 25^\circ\text{C}$
Current dissipation*2	Normal operation I_{CC}^{*4}	—	TBD	TBD	mA	$f = 20 \text{ MHz}$
	Sleep mode	—	TBD	TBD	mA	$f = 20 \text{ MHz}$
	Standby mode*3	—	0.01	5.0	μA	$T_a \leq 50^\circ\text{C}$ $50^\circ\text{C} < T_a$
Analog power supply current	During A/D conversion $A I_{CC}$	—	TBD	TBD	mA	
	Idle	—	0.01	5.0	μA	
Reference current	During A/D conversion $A I_{CC}$	—	TBD	TBD	mA	
	Idle	—	0.01	5.0	μA	
RAM standby voltage	V_{RAM}	2.0	—	—	V	

- Notes: 1. IF the A/D converter is not used, do not leave the AV_{CC} , AV_{SS} , and V_{ref} pins open. Connect AV_{CC} and V_{ref} to V_{CC} , and connect AV_{SS} to V_{SS} .
2. Current dissipation values are for $V_{IH} \text{ min} = V_{CC} - 0.5 \text{ V}$ and $V_{IL} \text{ max} = 0.5 \text{ V}$ with all output pins unloaded and the on-chip pull-up transistors in the off state.
3. The values are for $V_{RAM} \leq V_{CC} < 4.5 \text{ V}$, $V_{IH} \text{ min} = V_{CC} \times 0.9$, and $V_{IL} \text{ max} = 0.3 \text{ V}$.
4. I_{CC} depends on V_{CC} and f as follows:
 $I_{CC} \text{ max} = \text{TBD (mA)} + \text{TBD (mA/MHz.V)} \times V_{CC} \times f$ [normal mode]
 $I_{CC} \text{ max} = \text{TBD (mA)} + \text{TBD (mA/MHz.V)} \times V_{CC} \times f$ [sleep mode]

Table 22-2 DC Characteristics (cont)

– Preliminary –

Conditions: $V_{CC} = AV_{CC} = 2.7$ to 5.5 V $V_{ref} = 2.7$ V to AV_{CC} , $V_{SS} = AV_{SS} = 0$ V*1, $T_a = -20$ to $+75^\circ\text{C}$ (regular specifications), $T_a = -40$ to $+85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Min	Typ	Max	Unit	Test Conditions	
Schmitt trigger input voltage	Port 2, P6 ₄ to P6 ₇ , PA ₄ to PA ₇	V_T^-	$V_{CC} \times 0.2$	—	—	V	
		V_T^+	—	—	$V_{CC} \times 0.7$	V	
		$V_T^+ - V_T^-$	$V_{CC} \times 0.07$	—	—	V	
Input high voltage	RES, STBY, NMI, MD ₂ to MD ₀	V _{IH}	$V_{CC} \times 0.9$	—	$V_{CC} + 0.3$	V	
	EXTAL		$V_{CC} \times 0.7$	—	$V_{CC} + 0.3$	V	
	Port1, 3, 5, B to G, P6 ₀ to P6 ₃ , PA ₀ to PA ₃		$V_{CC} \times 0.7$	—	$V_{CC} + 0.3$	V	
	Port4		$V_{CC} \times 0.7$	—	$AV_{CC} + 0.3$	V	
Input low voltage	RES, STBY, MD ₂ to MD ₀	V _{IL}	-0.3	—	$V_{CC} \times 0.1$	V	
	NMI, EXTAL, Port1, 3 to 5, B to G, P6 ₀ to P6 ₃ , PA ₀ to PA ₃		-0.3	—	$V_{CC} \times 0.2$	V $V_{CC} < 4.0$ V	
Output high voltage	All output pins	V _{OH}	$V_{CC} - 0.5$	—	—	V	I _{OH} = -200 μA
			$V_{CC} - 1.0$	—	—	V	I _{OH} = -1 mA
Output low voltage	All output pins	V _{OL}	—	—	0.4	V	I _{OL} = 1.6 mA
			Port1, A to C	—	—	1.0	V
Input leakage current	STBY, RES, NMI, MD ₂ to MD ₀	I _{in}	—	—	1.0	μA	V _{IN} = 0.5 to $V_{CC} - 0.5$ V
	Port4		—	—	1.0	μA	V _{IN} = 0.5 to $AV_{CC} - 0.5$ V

Note: 1. IF the A/D converter is not used, do not leave the AV_{CC} , AV_{SS} , and V_{ref} pins open. Connect AV_{CC} and V_{REF} to V_{CC} , and connect AV_{SS} to V_{SS} .

Table 22-2 DC Characteristics (cont)

– Preliminary –

Conditions: $V_{CC} = AV_{CC} = 2.7$ to 5.5 V $V_{ref} = 2.7$ V to AV_{CC} , $V_{SS} = AV_{SS} = 0$ V*1, $T_a = -20$ to $+75^\circ\text{C}$ (regular specifications), $T_a = -40$ to $+85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Three-state leakage current (off state)	Port1 to 3, 5, 6, A to G $ I_{TSI} $	—	—	1.0	μA	$V_{IN} = 0.5$ to $V_{CC} - 0.5$ V
Input pull-up current	Port A to E $-I_p$	10	—	300	μA	$V_{CC} = 2.7$ V to 5.5 V, $V_{IN} = 0$ V
Input capacitance	NMI C_{IN}	—	—	50	pF	$V_{IN} = 0$ V $f = 1$ MHz $T_a = 25^\circ\text{C}$
	All input pins except NMI	—	—	15	pF	
Current dissipation*2	Normal operation I_{CC}^{*4}	—	TBD	TBD	mA	$f = 10$ MHz
	Sleep mode	—	TBD	TBD	mA	$f = 10$ MHz
	Standby mode*3	—	0.01	5.0	μA	$T_a \leq 50^\circ\text{C}$ $50^\circ\text{C} < T_a$
Analog power supply current	During A/D conversion $A_{I_{CC}}$	—	TBD	TBD	mA	
	Idle	—	0.01	5.0	μA	
Reference current	During A/D conversion $A_{I_{CC}}$	—	TBD	TBD	mA	
	Idle	—	0.01	5.0	μA	
RAM standby voltage	V_{RAM}	2.0	—	—	V	

- Notes: 1. IF the A/D converter is not used, do not leave the AV_{CC} , AV_{SS} , and V_{ref} pins open. Connect AV_{CC} and V_{REF} to V_{CC} , and connect AV_{SS} to V_{SS} .
2. Current dissipation values are for $V_{IH\ min} = V_{CC} - 0.5$ V and $V_{IL\ max} = 0.5$ V with all output pins unloaded and the on-chip pull-up transistors in the off state.
3. The values are for $V_{RAM} \leq V_{CC} < 2.7$ V, $V_{IH\ min} = V_{CC} \times 0.9$, and $V_{IL\ max} = 0.3$ V.
4. I_{CC} depends on V_{CC} and f as follows:
 $I_{CC\ max} = \text{TBD (mA)} + \text{TBD (mA/MHz} \times \text{V)} \times V_{CC} \times f$ [normal mode]
 $I_{CC\ max} = \text{TBD (mA)} + \text{TBD (mA/MHz} \times \text{V)} \times V_{CC} \times f$ [sleep mode]

Table 22-3 Permissible Output Currents

– Preliminary –

Conditions: $V_{CC} = AV_{CC} = 2.7$ to 5.5 V, $V_{ref} = 2.7$ to AV_{CC} , $V_{SS} = AV_{SS} = 0$ V, $T_a = -20$ to $+75^\circ\text{C}$ (regular specifications), $T_a = -40$ to $+85^\circ\text{C}$ (wide-range specifications)

Item		Symbol	Min	Typ	Max	Unit
Permissible output low current (per pin)	Port1, A to C	I_{OL}	—	—	10	mA
	Other output pins		—	—	2.0	mA
Permissible output low current (total)	Total of 32 pins including port1 and A to C	ΣI_{OL}	—	—	80	mA
	Total of all output pins, including the above		—	—	120	mA
Permissible output high current (per pin)	All output pins	$-I_{OH}$	—	—	2.0	mA
Permissible output high current (total)	Total of all output pins	$\Sigma -I_{OH}$	—	—	40	mA

- Notes: 1. To protect chip reliability, do not exceed the output current values in table 22-3.
 2. When driving a darlington pair or LED, always insert a current-limiting resistor in the output line, as show in figures 22-1 and 22-2.

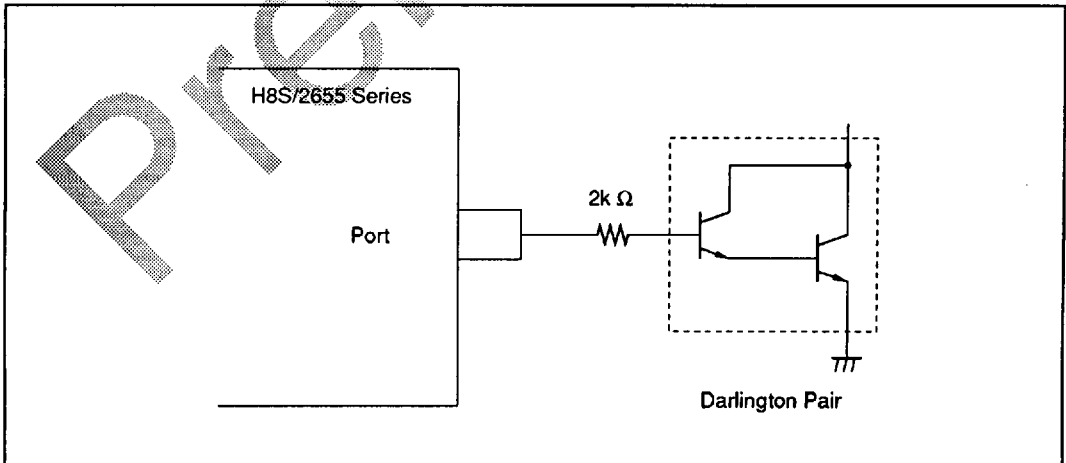


Figure 22-1 Darlington Pair Drive Circuit (Example)

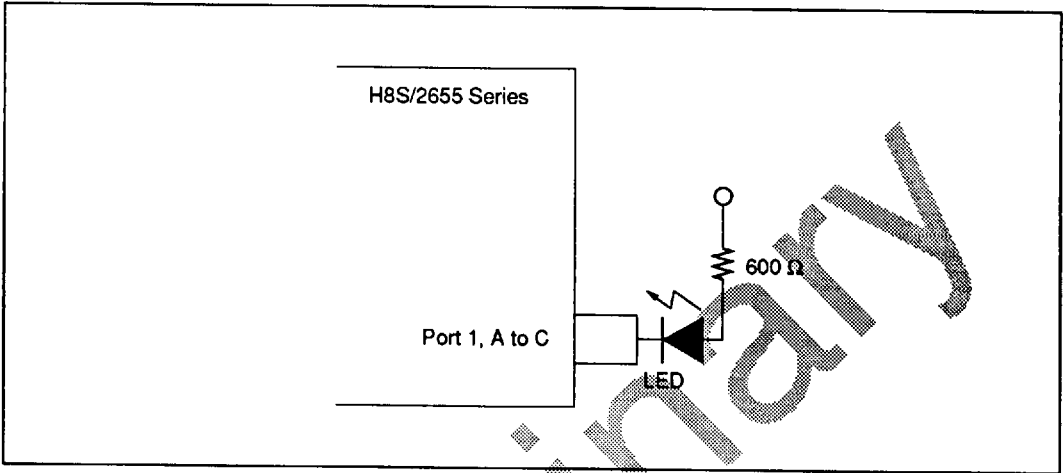


Figure 22-2 LED Drive Circuit (Example)

22.3 AC Characteristics

Figure 22-3 show, the test conditions for the AC characteristics.

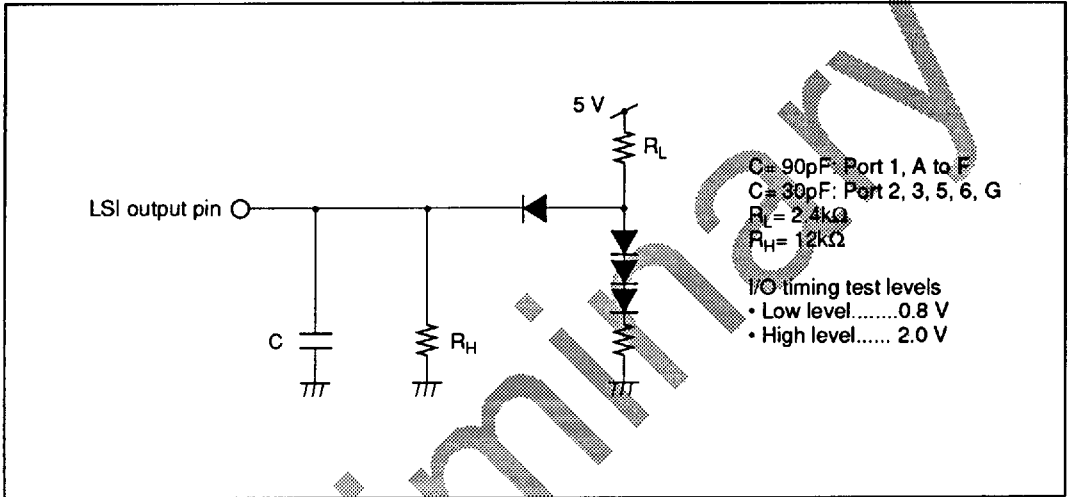


Figure 22-3. Output Load Circuit

22.3.1 Clock Timing

Table 22-4 lists the clock timing

Table 22-4 Clock Timing

– Preliminary –

Condition A: $V_{CC} = AV_{CC} = 2.7 \text{ V to } 5.5 \text{ V}$, $V_{ref} = 2.7 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V}$, $\phi = 2$ to 10 MHz , $T_a = -20 \text{ to } +75^\circ\text{C}$ (regular specifications), $T_a = -40 \text{ to } +85^\circ\text{C}$ (wide-range specifications)

Condition B: $V_{CC} = AV_{CC} = 5.0 \text{ V} \pm 10\%$, $V_{ref} = 4.5 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V}$, $\phi = 2$ to 20 MHz , $T_a = -20 \text{ to } +75^\circ\text{C}$ (regular specifications), $T_a = -40 \text{ to } +85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Min	Max	Unit	Test Conditions
Clock cycle time	t_{cyc}	50	2000	ns	22.4
Clock high pulse width	t_{CH}	20	—	ns	22.4
Clock low pulse width	t_{CL}	20	—	ns	
Clock rise time	t_{Cr}	—	5	ns	
Clock delay time	t_{Cf}	—	5	ns	
Clock oscillator setting time at reset (crystal)	t_{OSC1}	10	—	ms	22.5
Clock oscillator setting time in software standby (crystal)	t_{OSC2}	10	—	ms	
External clock output stabilization delay time	t_{DEXT}	500	—	μs	

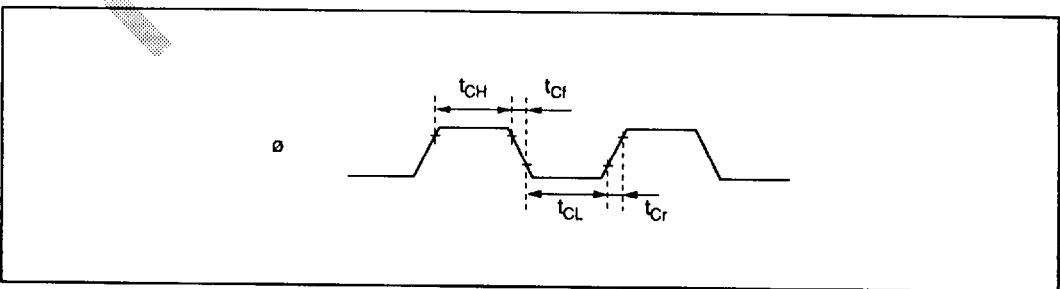


Figure 22-4 System Clock Timing

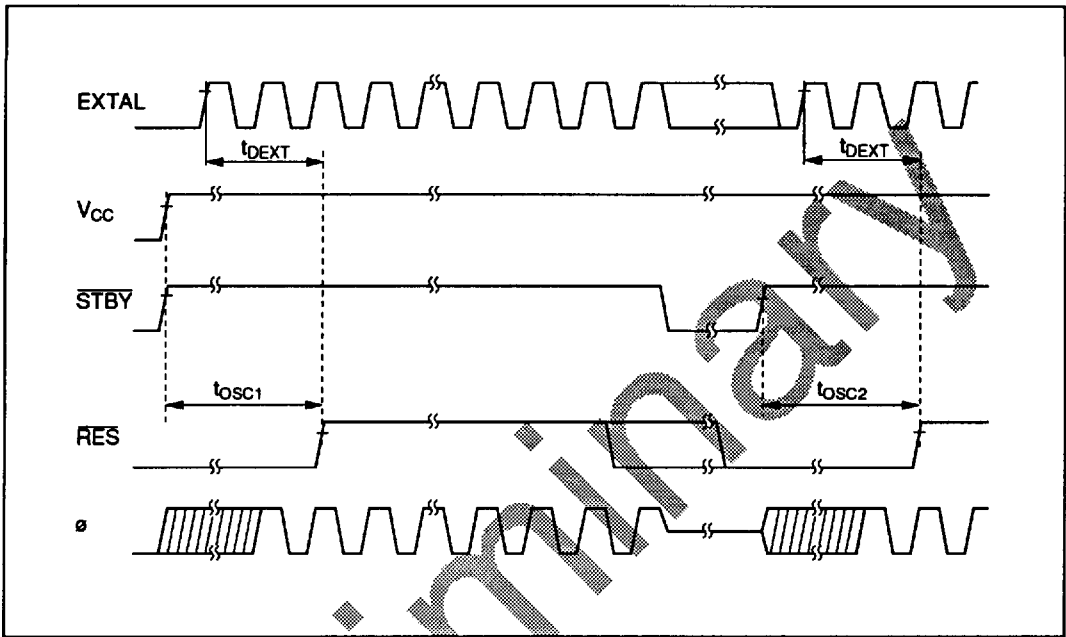


Figure 22-5 Oscillator Settling Timing

Preliminary

22.3.2 Control Signal Timing

Table 22-5 lists the control signal timing.

Table 22-5 Control Signal Timing

– Preliminary –

Condition A: $V_{CC} = AV_{CC} = 2.7 \text{ V to } 5.5 \text{ V}$, $V_{ref} = 2.7 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V}$, $\phi = 2$ to 10 MHz, $T_a = -20 \text{ to } +75^\circ\text{C}$ (regular specifications), $T_a = -40 \text{ to } +85^\circ\text{C}$ (wide-range specifications)

Condition B: $V_{CC} = AV_{CC} = 5.0 \text{ V} \pm 10\%$, $V_{ref} = 4.5 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V}$, $\phi = 2$ to 20 MHz, $T_a = -20 \text{ to } +75^\circ\text{C}$ (regular specifications), $T_a = -40 \text{ to } +85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Condition A		Condition B		Unit	Test Conditions
		Min	Max	Min	Max		
$\overline{\text{RES}}$ setup time	t_{RESS}	200	—	200	—	ns	Figure 22-6
$\overline{\text{RES}}$ pulse width	t_{RESW}	10	—	10	—	t_{cyc}	
NMI setup time	t_{NMIS}	150	—	150	—	ns	Figure 22-7
NMI hold time	t_{NMIH}	10	—	10	—		
NMI pulse width (exiting software standby mode)	t_{NMIW}	200	—	200	—	ns	
IRQ setup time	t_{IRQS}	150	—	150	—	ns	
IRQ hold time	t_{IRCH}	10	—	10	—	ns	
IRQ pulse width (exiting software standby mode)	t_{IRQW}	200	—	200	—	ns	

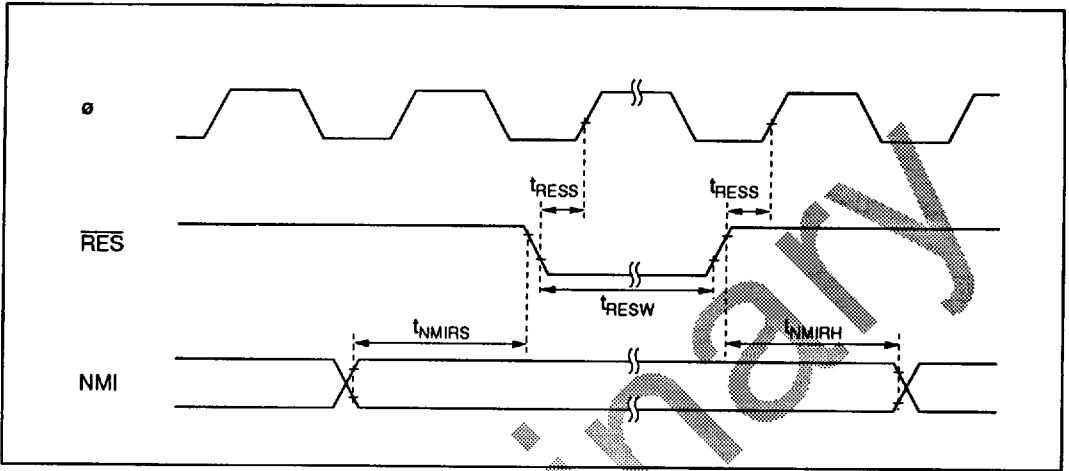


Figure 22-6 Reset Input Timing

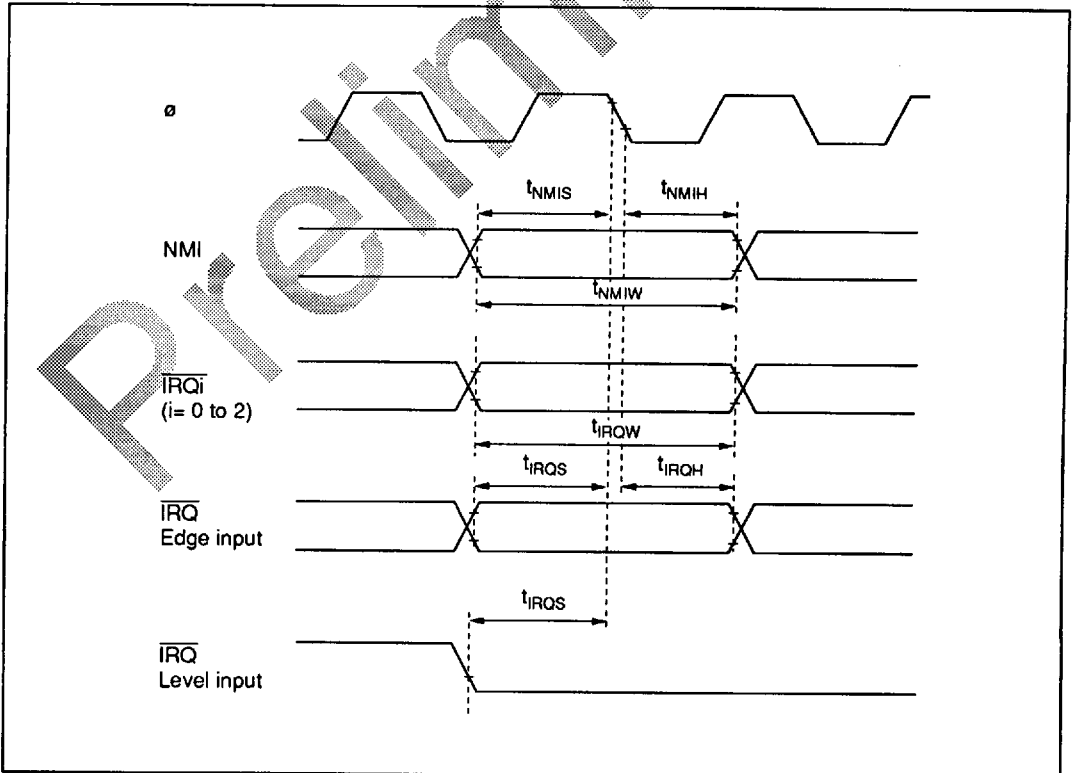


Figure 22-7 Interrupt Input Timing

22.3.3 Bus Timing

Table 22-6 lists the bus timing.

Table 22-6 Bus Timing

— Preliminary —

Condition A: $V_{CC} = AV_{CC} = 2.7 \text{ V to } 5.5 \text{ V}$, $V_{ref} = 2.7 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V}$, $\phi = 2$ to 10 MHz, $T_a = -20$ to $+75^\circ\text{C}$ (regular specifications), $T_a = -40$ to $+85^\circ\text{C}$ (wide-range specifications)

Condition B: $V_{CC} = AV_{CC} = 5.0 \text{ V} \pm 10\%$, $V_{ref} = 4.5 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V}$, $\phi = 2$ to 20 MHz, $T_a = -20$ to $+75^\circ\text{C}$ (regular specifications), $T_a = -40$ to $+85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Condition A		Condition B		Unit	Test Conditions
		Min	Max	Min	Max		
Address delay time	t_{AD}	—	40	—	20	ns	
Address setup time	t_{AS}	TBD	—	TBD	—	ns	
Address hold time	t_{AH}	TBD	—	TBD	—	ns	
Precharge time	t_{PCH}	1.5 x $t_{cyc -40}$	—	1.5 x $t_{cyc -20}$	—	ns	
\overline{CS} delay time 1	t_{CSD1}	—	40	—	20	ns	
\overline{CS} delay time 2	t_{CSD2}	—	40	—	20	ns	
\overline{CS} pulse width	t_{CSW}	2.5 x $t_{cyc -40}$	—	2.5 x $t_{cyc -20}$	—	ns	
\overline{AS} delay time	t_{ASD}	—	60	—	30	ns	
\overline{RD} delay time 1	t_{RSD1}	—	60	—	30	ns	
\overline{RD} delay time 2	t_{RSD2}	—	60	—	30	ns	
\overline{CAS} delay time	t_{CASD}	—	40	—	20	ns	
Read data setup time	t_{RDS}	—	30	—	15	ns	
Read data hold time	t_{RDH}	—	0	—	0	ns	
Read data access time1	t_{ACC1}	—	1.0 x $t_{cyc -50}$	—	1.0 x $t_{cyc -25}$	ns	
Read data access time2	t_{ACC2}	—	1.5 x $t_{cyc -50}$	—	1.5 x $t_{cyc -25}$	ns	
Read data access time3	t_{ACC3}	—	2.0 x $t_{cyc -50}$	—	2.0 x $t_{cyc -25}$	ns	
Read data access time4	t_{ACC4}	—	2.5 x $t_{cyc -50}$	—	2.5 x $t_{cyc -25}$	ns	

Table 22-6 Bus Timing (cont)

– Preliminary –

Condition A: $V_{CC} = AV_{CC} = 2.7\text{ V to }5.5\text{ V}$, $V_{ref} = 2.7\text{ V to }AV_{CC}$, $V_{SS} = AV_{SS} = 0\text{ V}$, $\phi = 2\text{ to }10\text{ MHz}$, $T_a = -20\text{ to }+75^\circ\text{C}$ (regular specifications), $T_a = -40\text{ to }+85^\circ\text{C}$ (wide-range specifications)

Condition B: $V_{CC} = AV_{CC} = 5.0\text{ V} \pm 10\%$, $V_{ref} = 4.5\text{ V to }AV_{CC}$, $V_{SS} = AV_{SS} = 0\text{ V}$, $\phi = 2\text{ to }20\text{ MHz}$, $T_a = -20\text{ to }+75^\circ\text{C}$ (regular specifications), $T_a = -40\text{ to }+85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Condition A		Condition B		Unit	Test Conditions
		Min	Max	Min	Max		
Read data access time ⁵	t_{ACC5}	—	$3.0 \times t_{cyc-50}$	—	$3.0 \times t_{cyc-25}$	ns	
\overline{WR} delay time 1	t_{WRD1}	—	60	—	30	ns	
\overline{WR} delay time 2	t_{WRD2}	—	60	—	30	ns	
\overline{WR} pulse width 1	t_{WSW1}	—	$1.0 \times t_{cyc-40}$	—	$1.0 \times t_{cyc-20}$	ns	
\overline{WR} pulse width 2	t_{WSW2}	—	$1.5 \times t_{cyc-0}$	—	$1.5 \times t_{cyc-20}$	ns	
Write data delay time	t_{WDD}	—	TBD	—	TBD	ns	
Write data setup time	t_{WDS}	0	—	0	—	ns	
Write data hold time	t_{WDH}	20	—	10	—	ns	
\overline{WR} setup time	t_{WCS}	$0.5 \times t_{cyc-20}$	—	$0.5 \times t_{cyc-10}$	—	ns	
\overline{WR} hold time	t_{WHS}	$0.5 \times t_{cyc-20}$	—	$0.5 \times t_{cyc-10}$	—	ns	
CAS setup time	t_{CSR}	$0.5 \times t_{cyc-20}$	—	$0.5 \times t_{cyc-10}$	—	ns	
\overline{WAIT} setup time	t_{WTS}	60	—	30	—	ns	
\overline{WAIT} hold time	t_{WTH}	10	—	5	—	ns	
\overline{BREQ} setup time	t_{BRQS}	60	—	30	—	ns	
\overline{BACK} delay time	t_{BACD}	—	60	—	30	ns	
Bus-floating time	t_{BZD}	—	100	—	50	ns	
\overline{BREQO} delay time	t_{BRQOD}	—	60	—	30	ns	

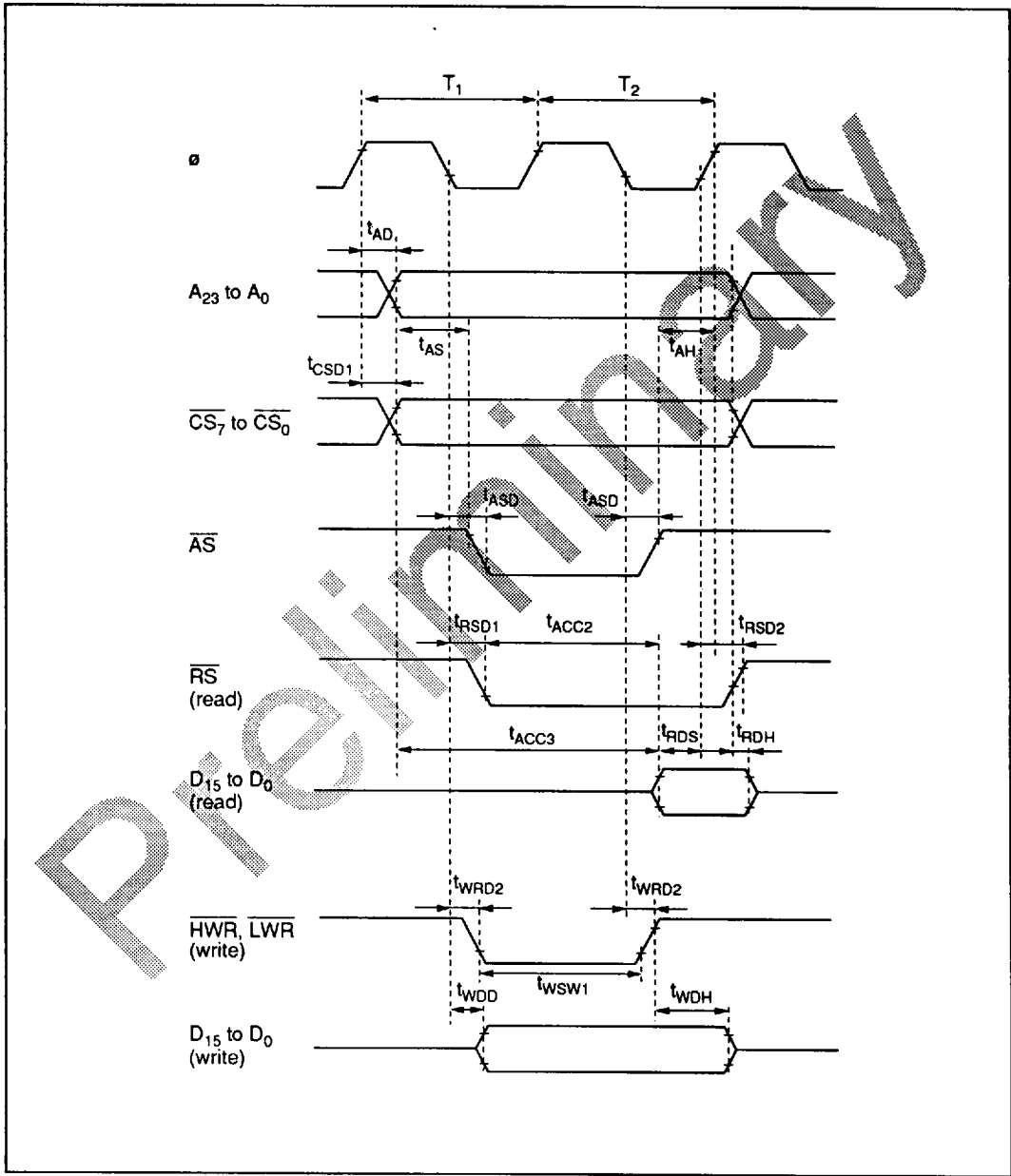


Figure 22-8 Basic Bus Timing: Two-State Access

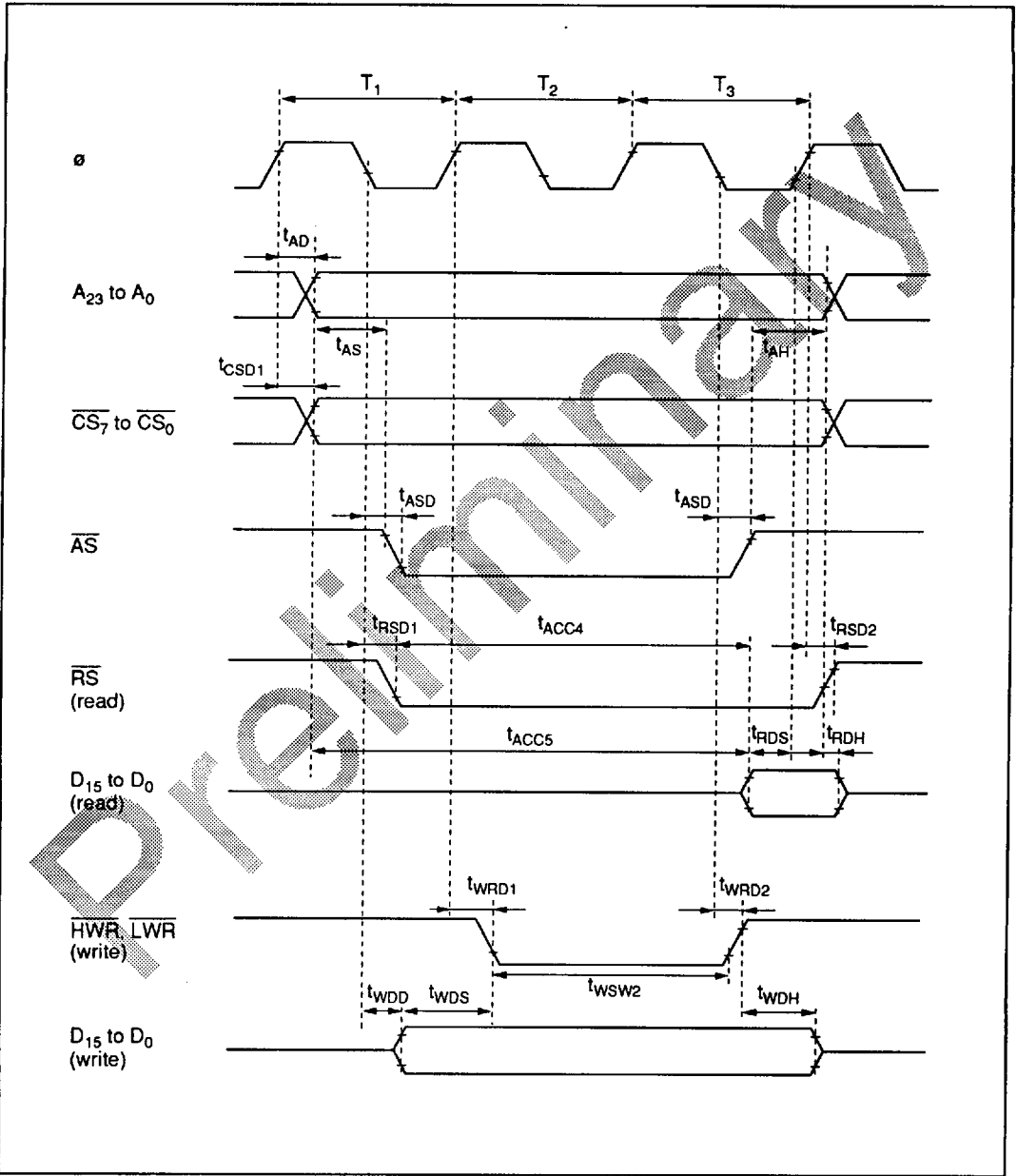


Figure 22-9 Basic Bus Timing: Three-State Access

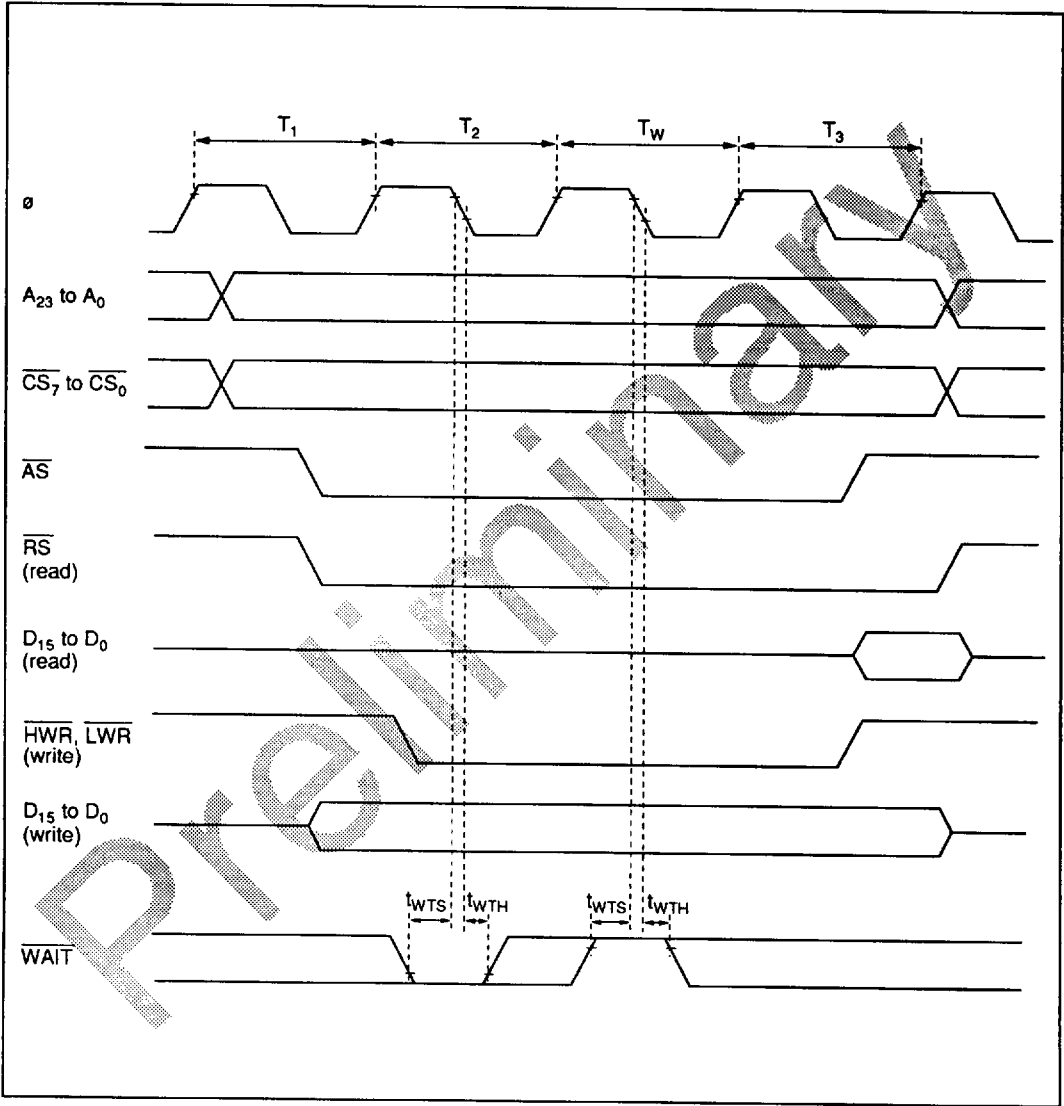


Figure 22-10 Basic Bus Timing: Three-State Access with One Wait State

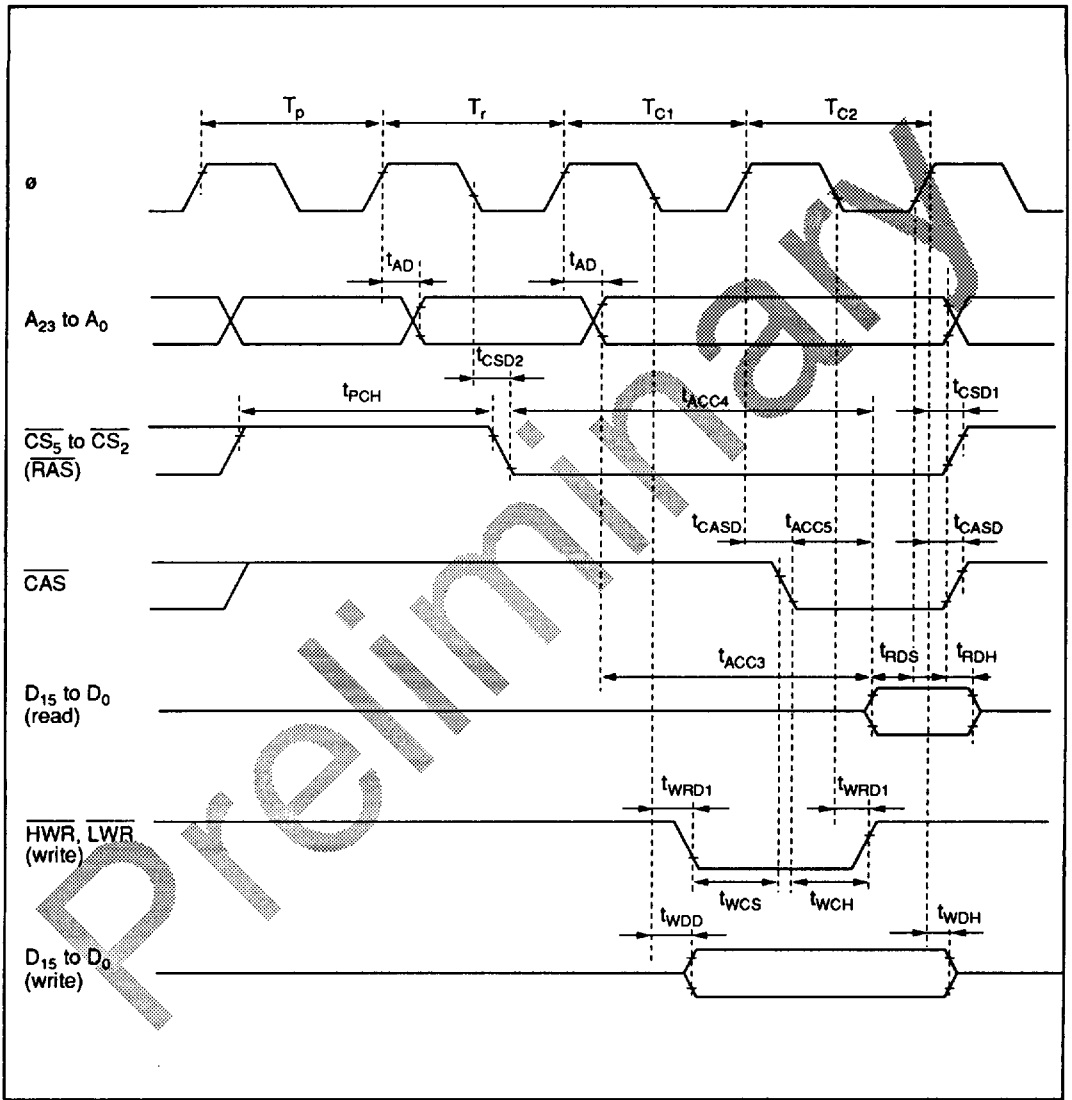


Figure 22-11 DRAM Bus Timing

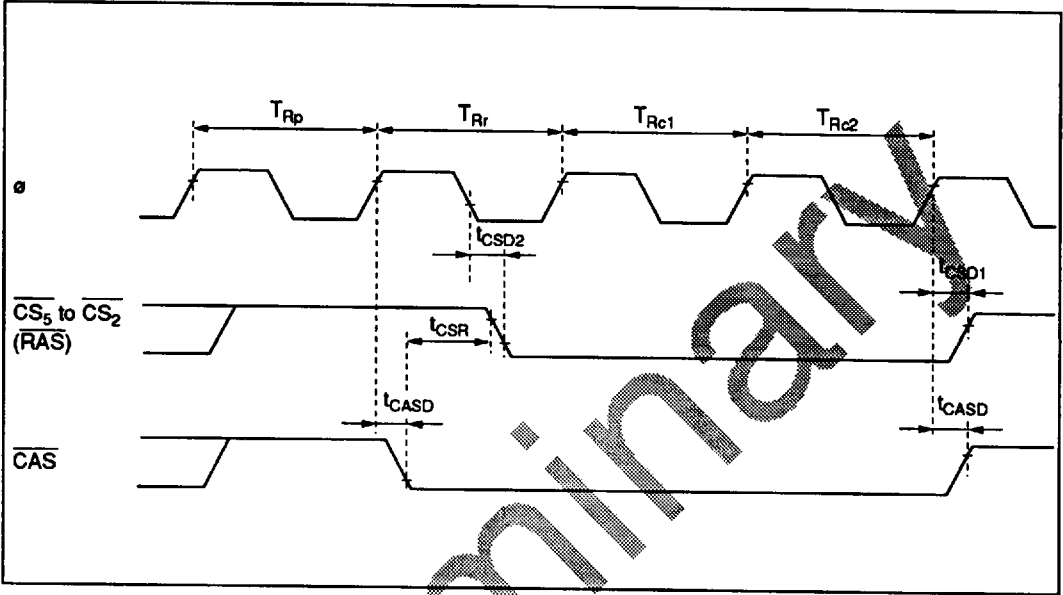


Figure 22-12 CAS-Before-RAS Refresh Timing

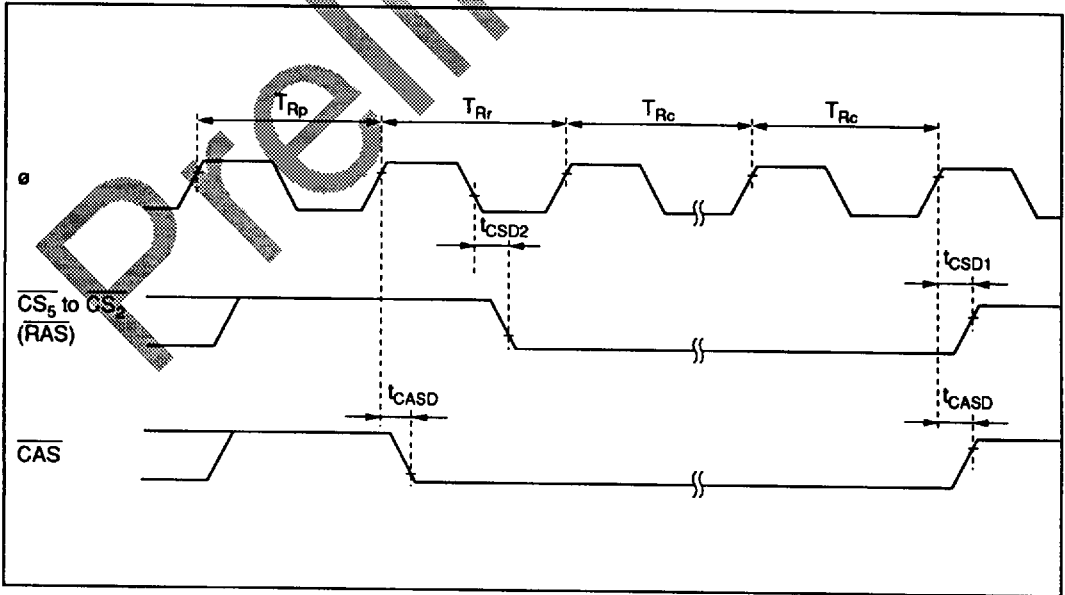


Figure 22-13 Self-Refresh Timing

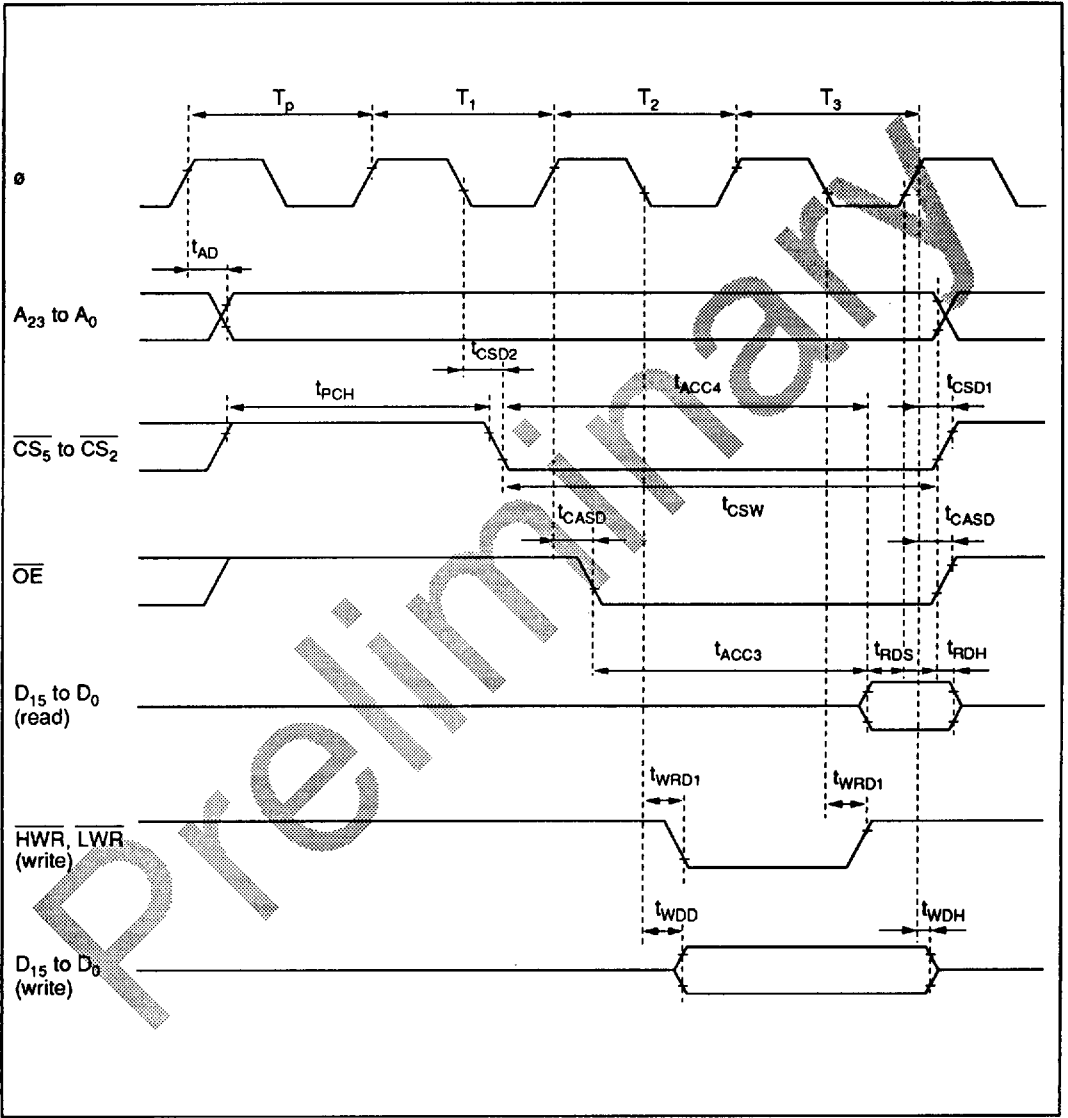


Figure 22-14 PSRAM Bus Timing

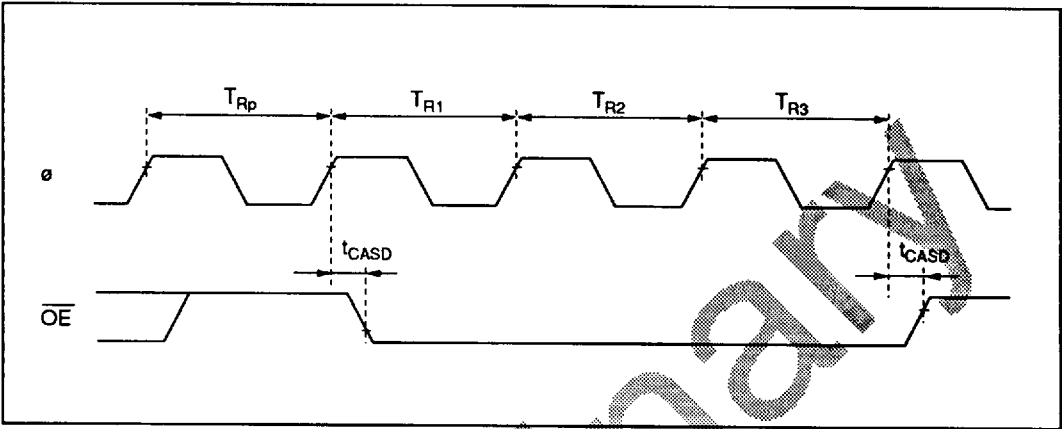


Figure 22-15 Auto Refresh Timing

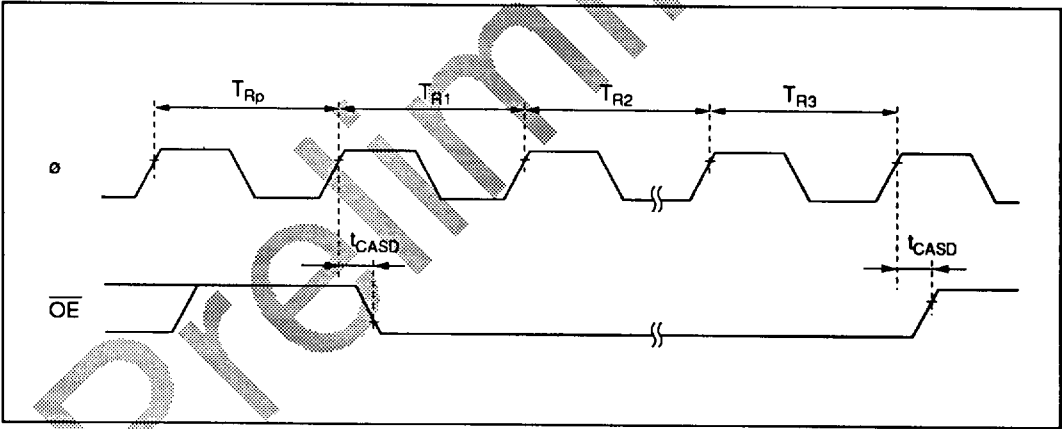


Figure 22-16 Self-Refresh Timing

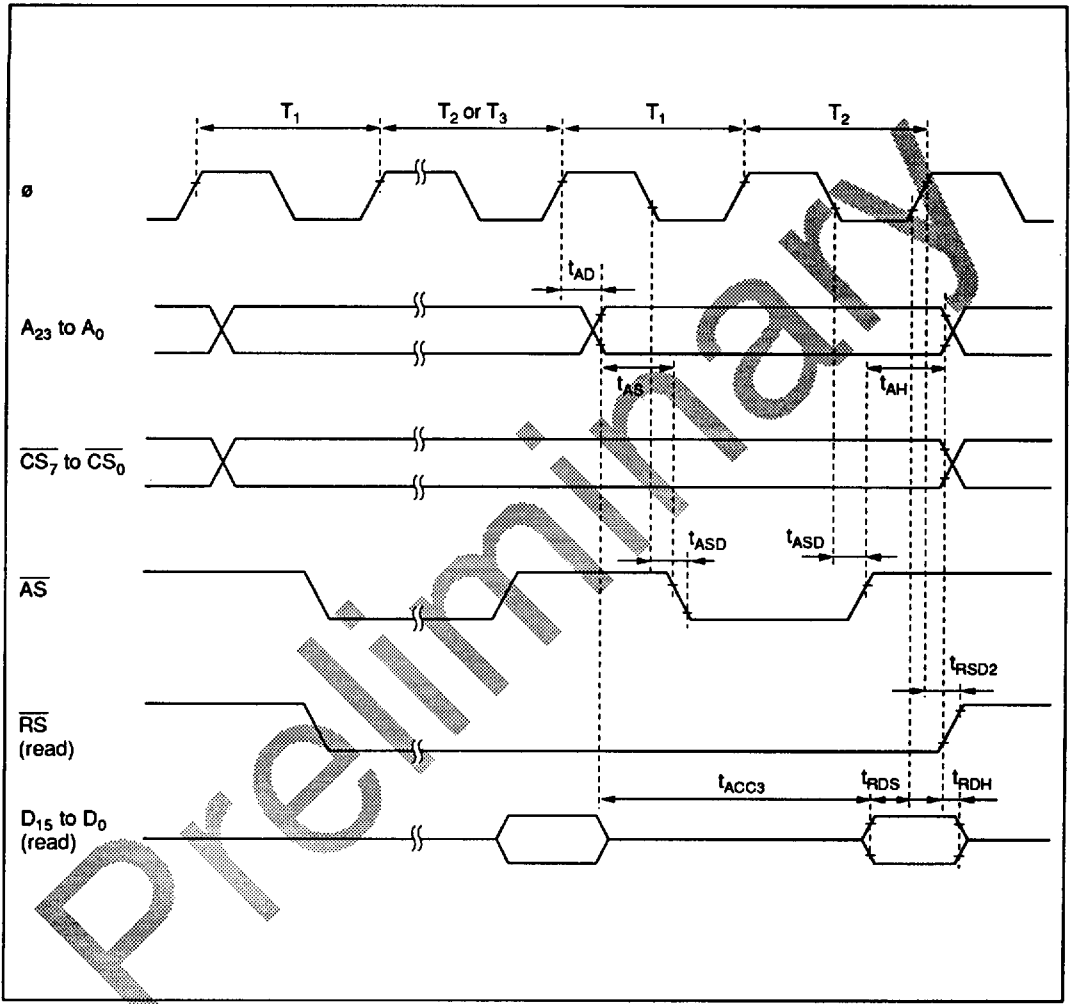


Figure 22-17 Burst ROM Access Timing: Two-State Access

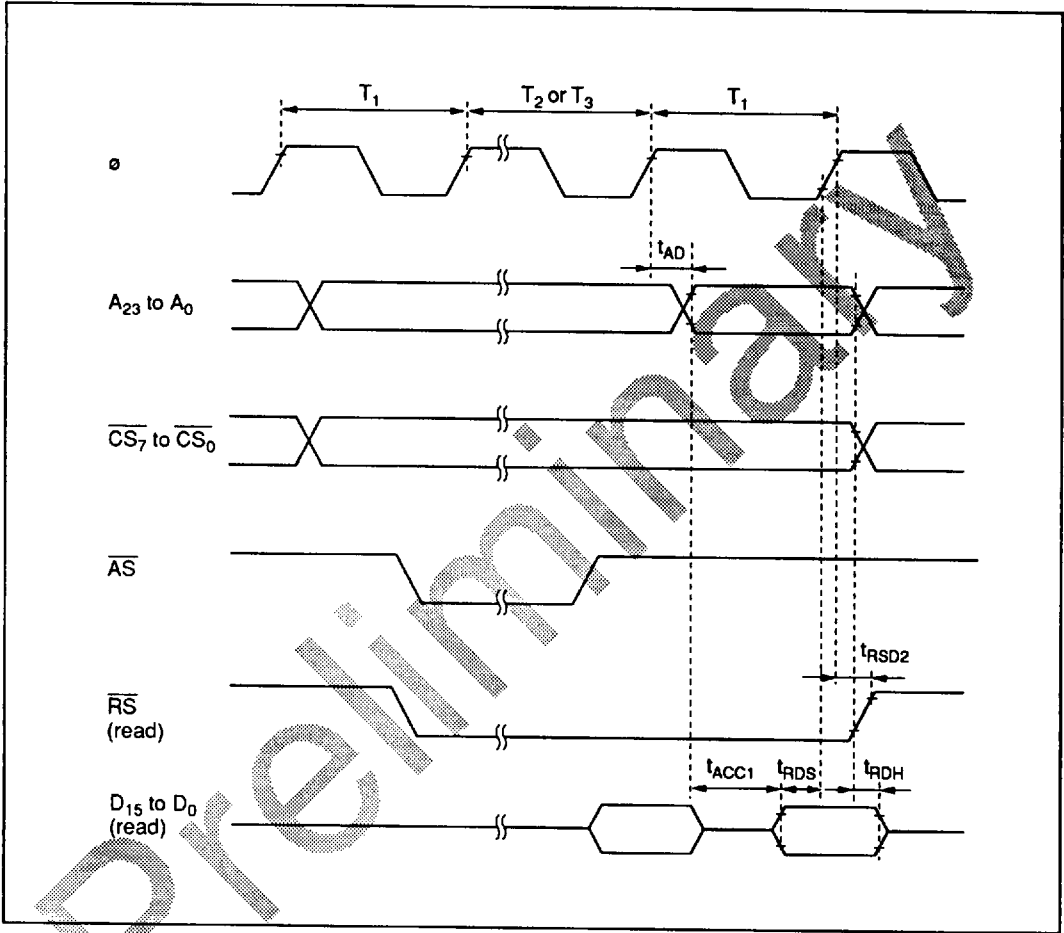


Figure 22-18 Burst ROM Access Timing: One-State Access

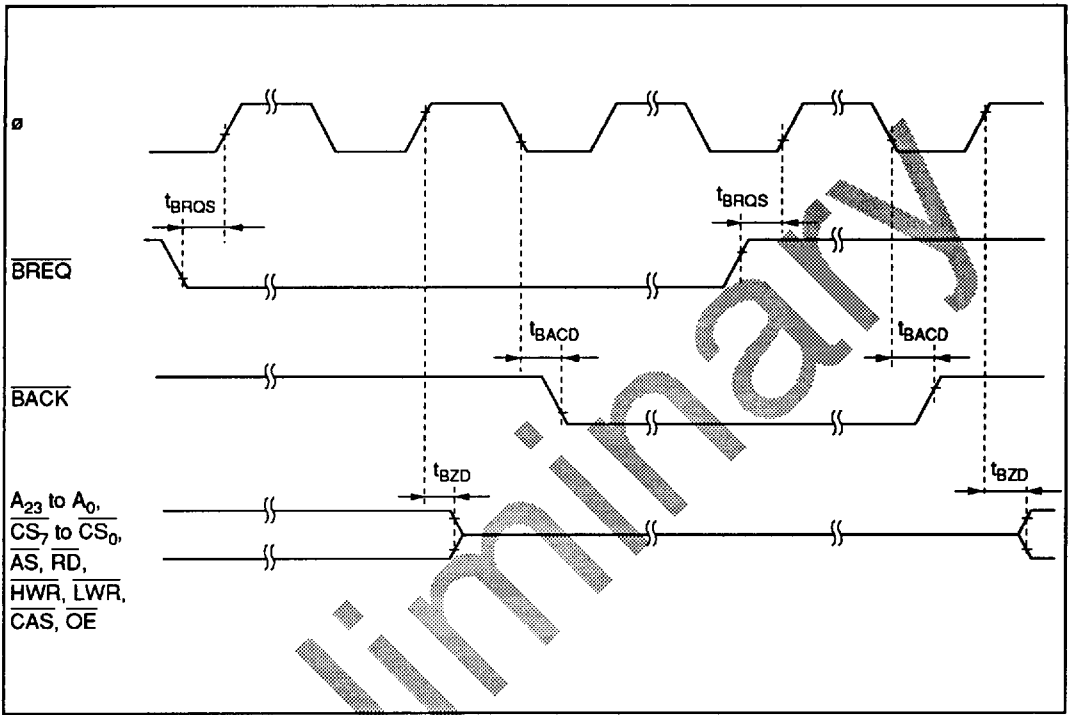


Figure 22-19 External Bus Release Timing

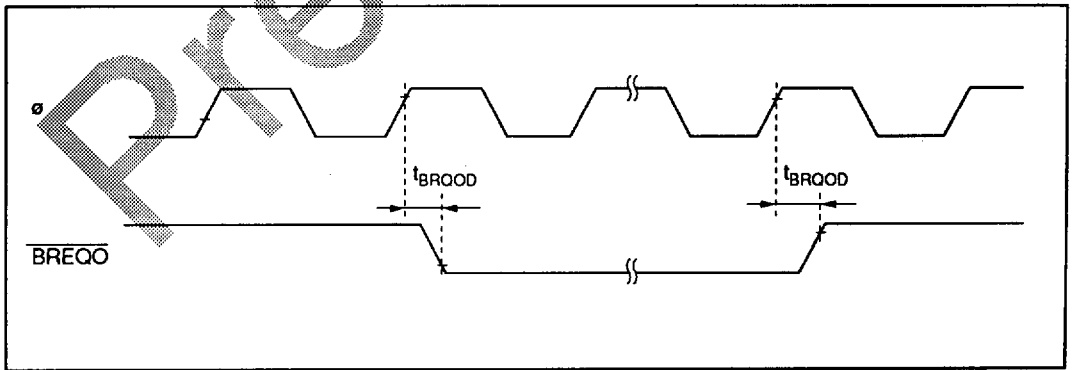


Figure 22-20 External Bus Request Output Timing

22.3.4 DMAC Timing

Table 22-7 lists the DMAC timing.

Table 22-7 DMAC Timing

– Preliminary –

Condition A: $V_{CC} = AV_{CC} = 2.7 \text{ V to } 5.5 \text{ V}$, $V_{ref} = 2.7 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V}$, $\phi = 2$ to 10 MHz, $T_a = -20$ to $+75^\circ\text{C}$ (regular specifications), $T_a = -40$ to $+85^\circ\text{C}$ (wide-range specifications)

Condition B: $V_{CC} = AV_{CC} = 5.0 \text{ V} \pm 10\%$, $V_{ref} = 4.5 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V}$, $\phi = 2$ to 20 MHz, $T_a = -20$ to $+75^\circ\text{C}$ (regular specifications), $T_a = -40$ to $+85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Condition A		Condition B		Unit	Test Conditions
		Min	Max	Min	Max		
$\overline{\text{DREQ}}$ setup time	t_{DRQS}	40	—	30	—	ns	Figure 22-24
$\overline{\text{DREQ}}$ hold time	t_{DROH}	10	—	10	—		
TEND delay time	t_{TED}	—	60	—	30		Figure 22-23
$\overline{\text{DACK}}$ delay time 1	t_{DACD1}	—	60	—	30	ns	Figure 22-21,
$\overline{\text{DACK}}$ delay time 2	t_{DACD2}	—	60	—	30		Figure 22-22

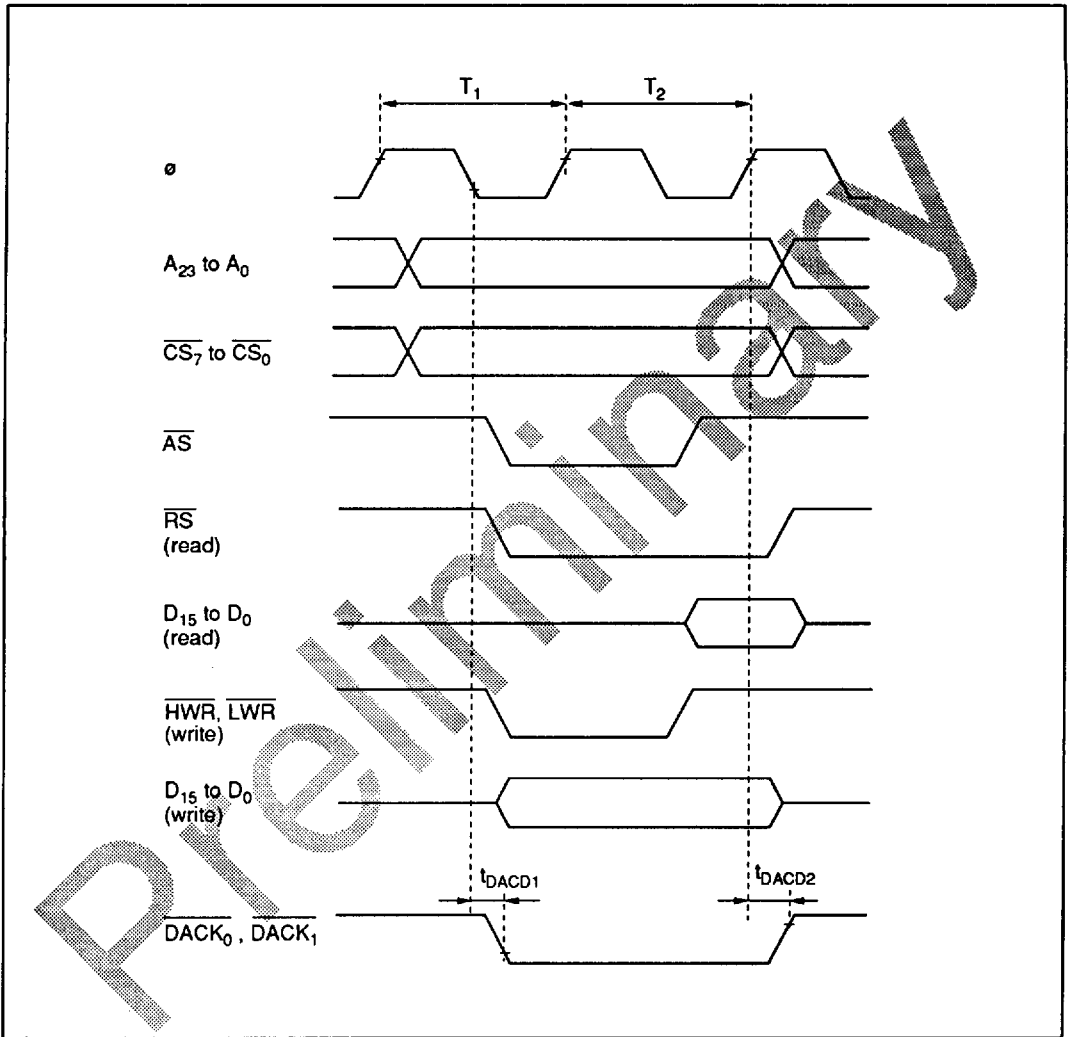


Figure 22-21 DMAC Single Address Transfer Timing: Two-State Access

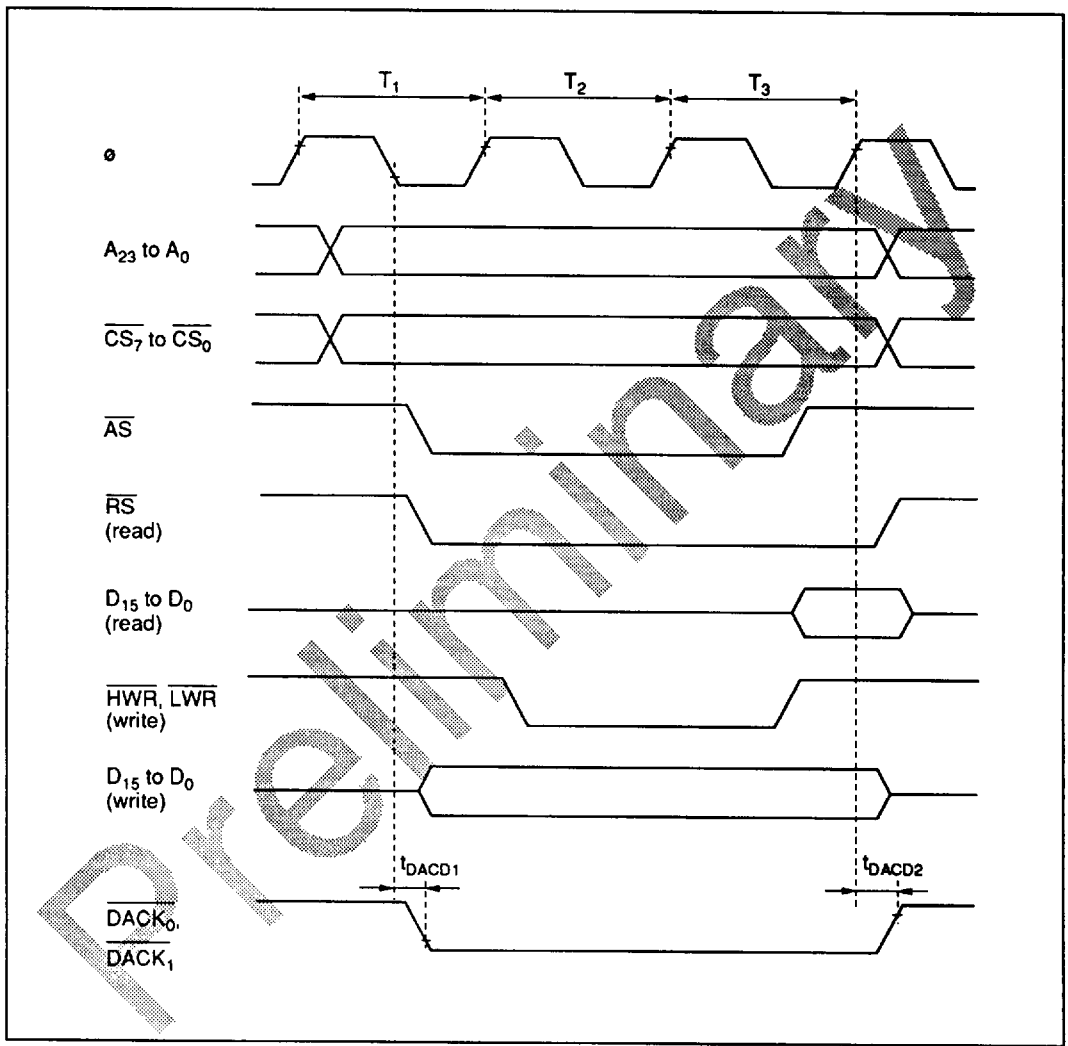


Figure 22-22 DMAC Single Address Transfer Timing: Three-State Access

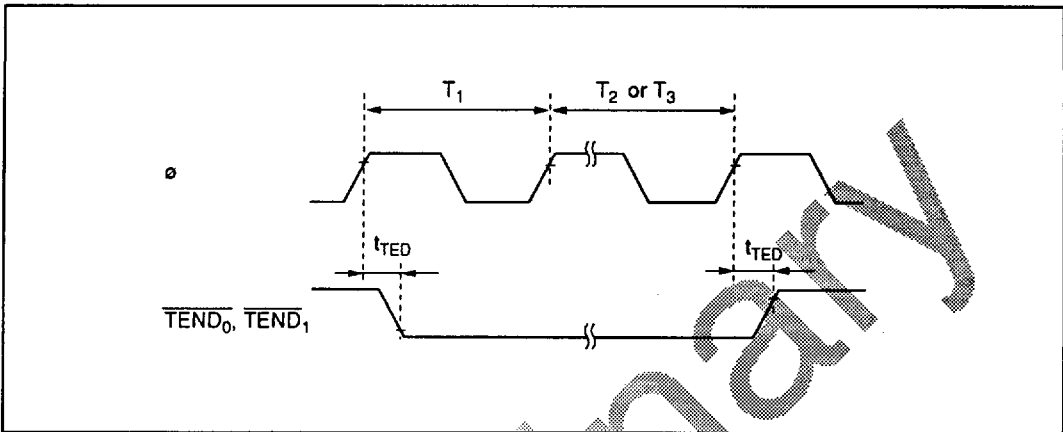


Figure 22-23 DMAC \overline{TEND} Output Timing

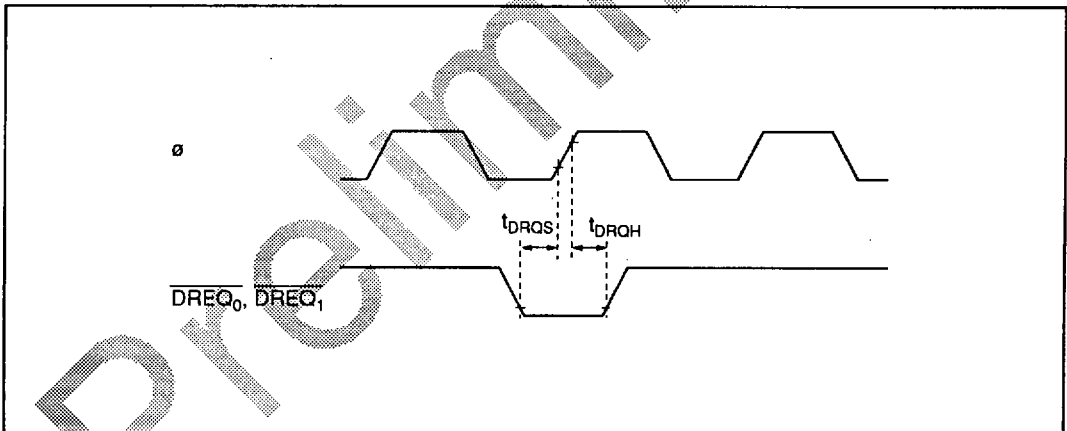


Figure 22-24 DMAC \overline{DREQ} Input Timing

22.3.5 Timing of On-Chip Supporting Modules

Table 22-8 lists the timing of on-chip supporting modules.

Table 22-8 Timing of On-Chip Supporting Modules

Preliminary –

Condition A: $V_{CC} = AV_{CC} = 2.7\text{ V to }5.5\text{ V}$, $V_{ref} = 2.7\text{ V to }AV_{CC}$, $V_{SS} = AV_{SS} = 0\text{ V}$, $\phi = 2$ to 10 MHz, $T_a = -20$ to $+75^\circ\text{C}$ (regular specifications), $T_a = -40$ to $+85^\circ\text{C}$ (wide-range specifications)

Condition B: $V_{CC} = AV_{CC} = 5.0\text{ V} \pm 10\%$, $V_{ref} = 4.5\text{ V to }AV_{CC}$, $V_{SS} = AV_{SS} = 0\text{ V}$, $\phi = 2$ to 20 MHz, $T_a = -20$ to $+75^\circ\text{C}$ (regular specifications), $T_a = -40$ to $+85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Condition A		Condition B		Unit	Test Conditions	
		Min	Max	Min	Max			
PORT	Output data delay time	t_{PWD}	—	100	—	50	ns	Figure 22-25
	Input data setup time	t_{PRS}	50	—	30	—		
	Input data hold time	t_{PRH}	50	—	30	—		
PPG	Pulse output delay time	t_{POD}	—	100	—	50	ns	Figure 22-26
TPU	Timer output delay time	t_{TOCD}	—	100	—	50	ns	Figure 22-27
	Timer input setup time	t_{TICS}	50	—	30	—		
	Timer clock input setup time	t_{TCKS}	50	—	30	—	ns	Figure 22-28
	Timer clock pulse width	Single edge t_{TCKWH} Both edges t_{TCKWL}	1.5 2.5	— —	1.5 2.5	— —	t_{cyc}	
TMR	Timer output delay time	t_{TMOD}	—	100	—	50	ns	Figure 22-29
	Timer reset input setup time	t_{TMRS}	50	—	30	—	ns	Figure 22-31
	Timer clock input setup time	t_{TMCS}	50	—	30	—	ns	Figure 22-30

Table 22-8 Timing of On-Chip Supporting Modules (cont)

– Preliminary –

Condition A: $V_{CC} = AV_{CC} = 2.7\text{ V to }5.5\text{ V}$, $V_{ref} = 2.7\text{ V to }AV_{CC}$, $V_{SS} = AV_{SS} = 0\text{ V}$, $\phi = 2$ to 10 MHz , $T_a = -20\text{ to }+75^\circ\text{C}$ (regular specifications), $T_a = -40\text{ to }+85^\circ\text{C}$ (wide-range specifications)

Condition B: $V_{CC} = AV_{CC} = 5.0\text{ V} \pm 10\%$, $V_{ref} = 4.5\text{ V to }AV_{CC}$, $V_{SS} = AV_{SS} = 0\text{ V}$, $\phi = 2$ to 20 MHz , $T_a = -20\text{ to }+75^\circ\text{C}$ (regular specifications), $T_a = -40\text{ to }+85^\circ\text{C}$ (wide-range specifications)

Item	Symbol	Condition A		Condition B		Unit	Test Conditions
		Min	Max	Min	Max		
TMR Timer clock pulse width	Single edge t_{TMCWH}	1.5	—	1.5	—	t_{cyc}	Figure 22-30
	Both edges t_{TMCWL}	2.5	—	2.5	—		
WDT Overflow output delay time	t_{WOVD}	—	100	—	50	ns	Figure 22-32
SCI Input clock cycle	Asynchronous t_{Scyc}	4	—	4	—	t_{cyc}	Figure 22-33
	Synchronous	6	—	6	—		
	Input clock pulse width t_{SCKW}	0.4	0.6	0.4	0.6	t_{Scyc}	
	Input clock rise time t_{SCKr}	—	1.5	—	1.5	t_{cyc}	
	Input clock fall time t_{SCKf}	—	1.5	—	1.5		
	Transmit data delay time t_{TXD}	—	100	—	50	ns	Figure 22-34
	Receive data setup time (synchronous) t_{RXS}	100	—	50	—	ns	
	Receive data hold time (synchronous) t_{RXH}	100	—	50	—	ns	
A/D converter Trigger input setup time	t_{RGS}	50	—	30	—	t_{ns}	Figure 22-35

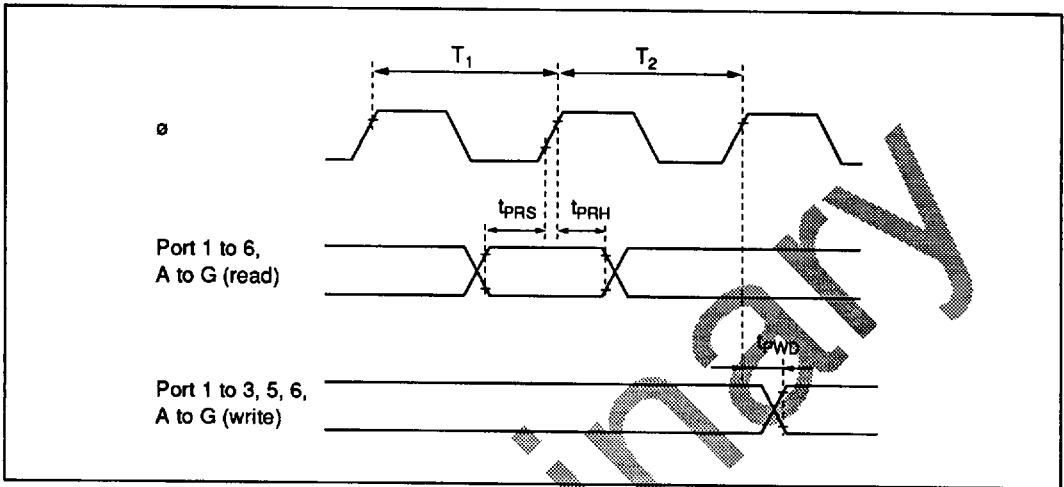


Figure 22-25 I/O Port Input/Output Timing

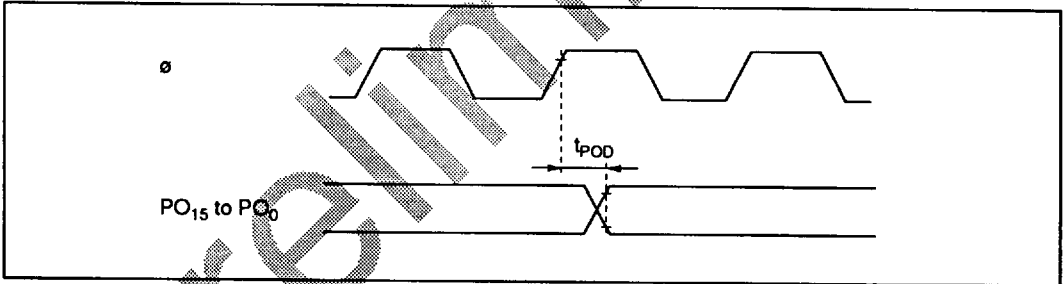


Figure 22-26 PPG Output Timing

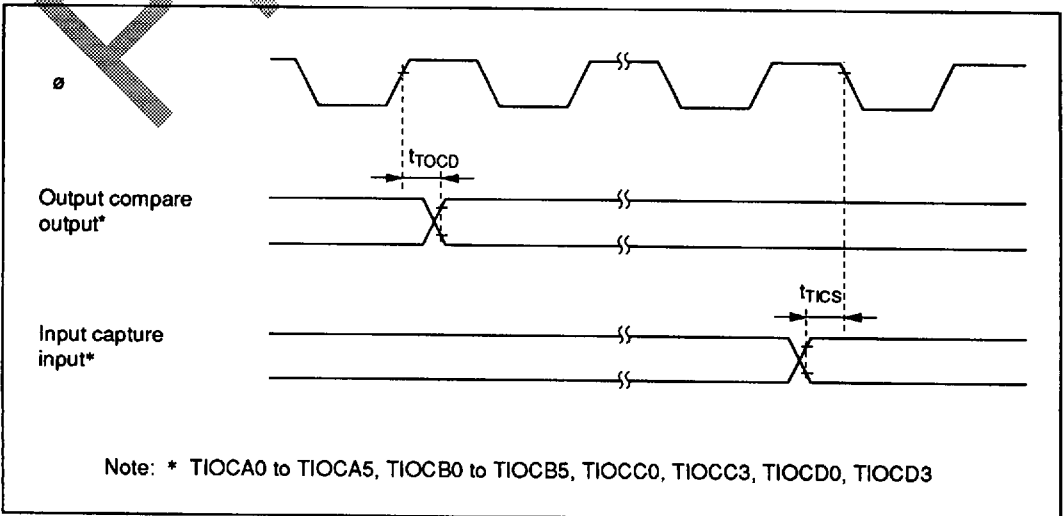


Figure 22-27 TPU Input/Output Timing

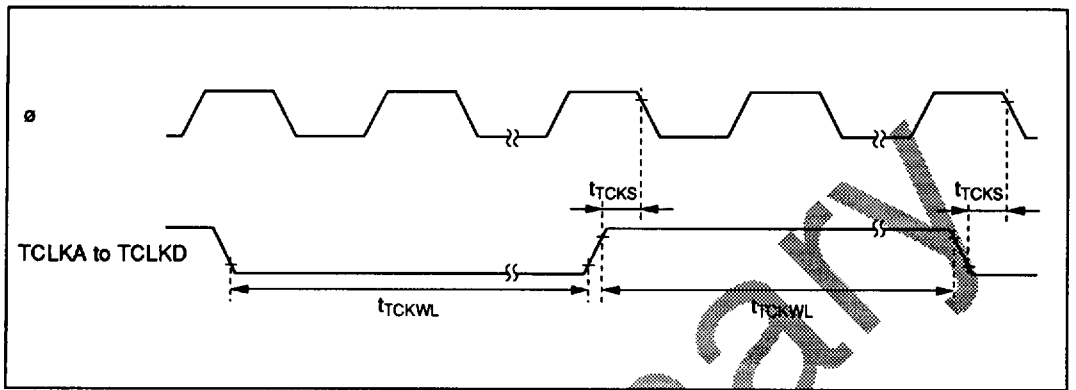


Figure 22-28 TPU Clock Input Timing

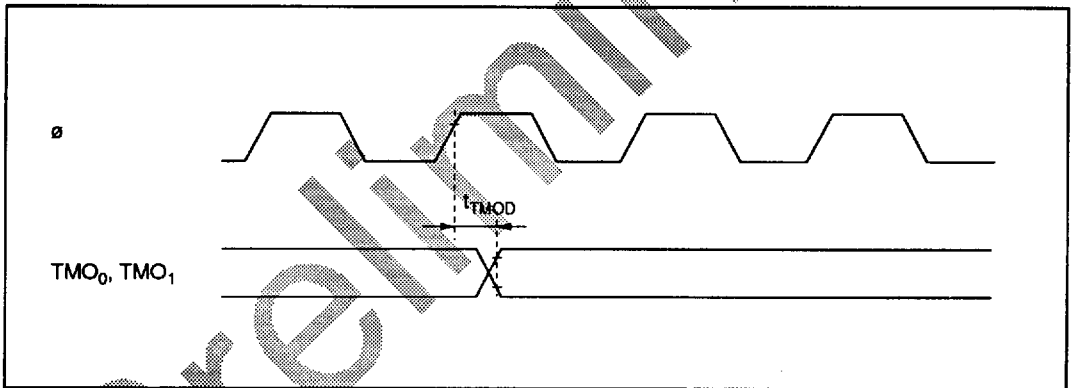


Figure 22-29 8-Bit Timer Output Timing

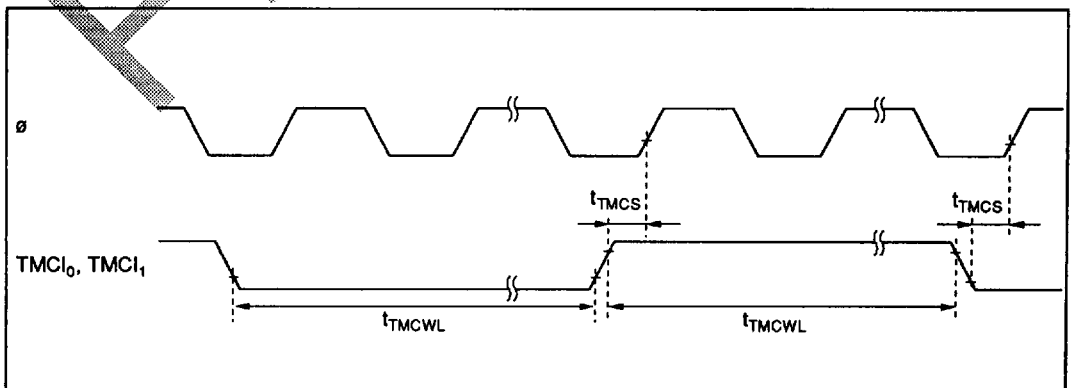


Figure 22-30 8-Bit Timer Clock Input Timing

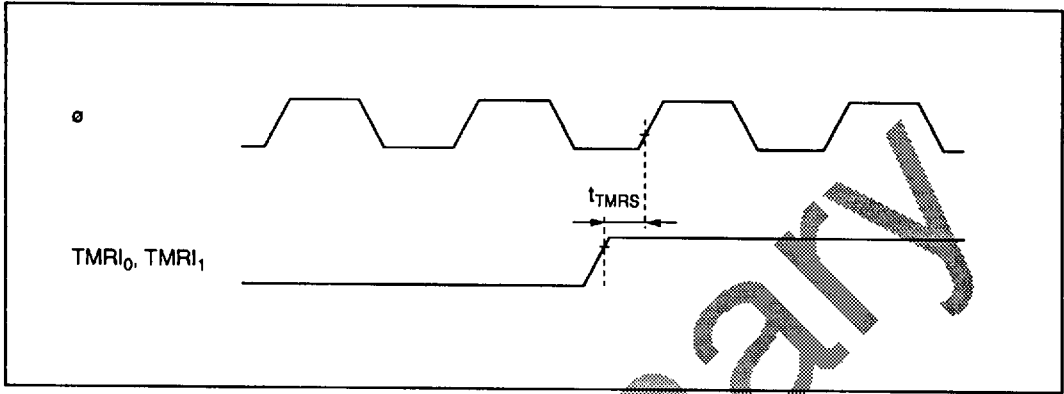


Figure 22-31 8-Bit Timer Reset Input Timing

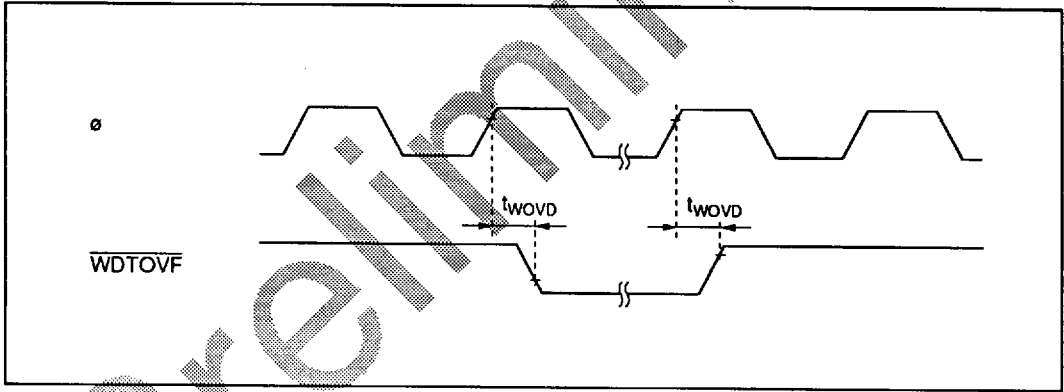


Figure 22-32 WDT Output Timing

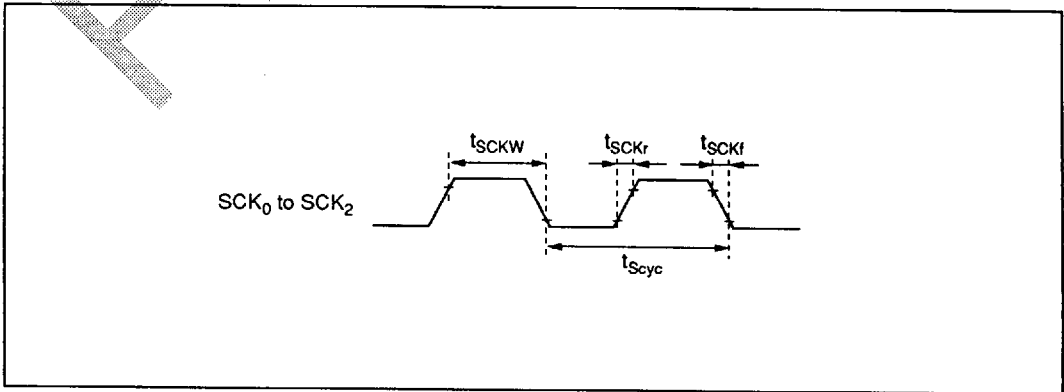


Figure 22-33 SCK Clock Input Timing

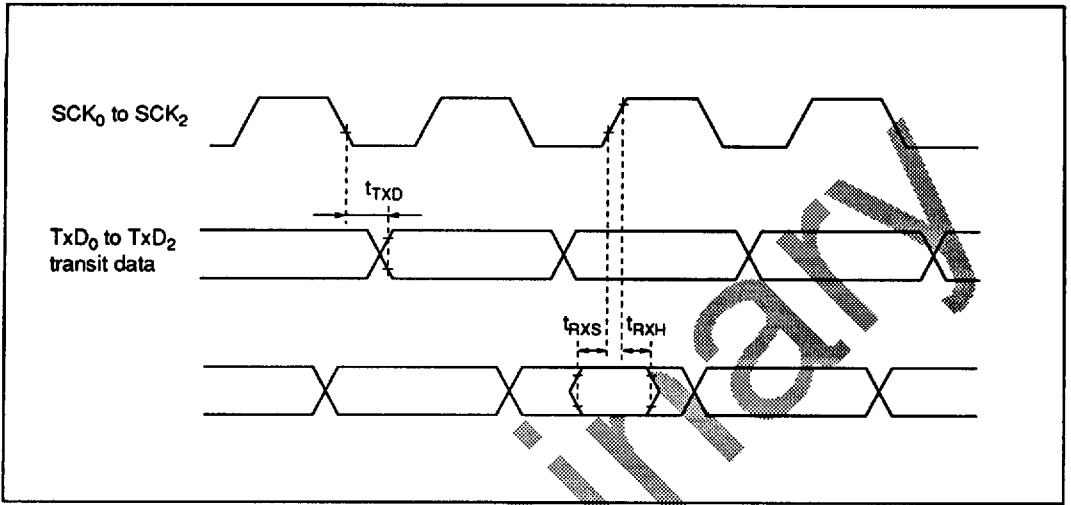


Figure 22-34 SCI Input/Output Timing Synchronous Mode

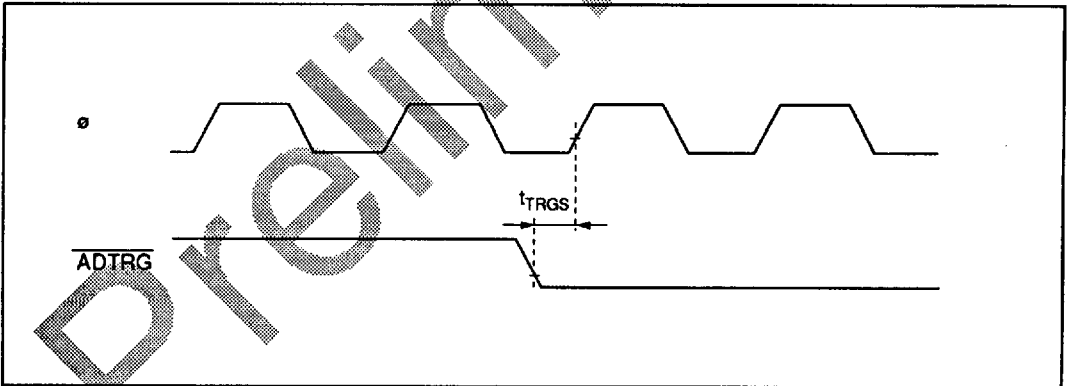


Figure 22-35 A/D Converter External Trigger Input Timing

22.4 A/D Conversion Characteristics

Table 22-9 lists the A/D conversion characteristics.

Table 22.9 A/D Conversion Characteristics

Preliminary –

Condition A: $V_{CC} = AV_{CC} = 2.7 \text{ V to } 5.5 \text{ V}$, $V_{ref} = 2.7 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V}$, $\phi = 2$ to 10 MHz , $T_a = -20 \text{ to } +75^\circ\text{C}$ (regular specifications), $T_a = -40 \text{ to } +85^\circ\text{C}$ (wide-range specifications)

Condition B: $V_{CC} = AV_{CC} = 5.0 \text{ V} \pm 10\%$, $V_{ref} = 4.5 \text{ V to } AV_{CC}$, $V_{SS} = AV_{SS} = 0 \text{ V}$, $\phi = 2$ to 20 MHz , $T_a = -20 \text{ to } +75^\circ\text{C}$ (regular specifications), $T_a = -40 \text{ to } +85^\circ\text{C}$ (wide-range specifications)

Item	Condition A			Condition B			Unit
	Min	Typ	Max	Min	Typ	Max	
Resolution	10	10	10	10	10	10	bits
Conversion time	—	—	TBD	—	—	TBD	μs
Analog input capacitance	—	—	TBD	—	—	TBD	pF
Permissible signal-source impedance	—	—	TBD	—	—	TBD	$\text{k}\Omega$
Nonlinearity error	—	—	TBD	—	—	TBD	LSB
Offset error	—	—	TBD	—	—	TBD	LSB
Full-scale error	—	—	TBD	—	—	TBD	LSB
Quantization	—	—	± 0.5	—	—	± 0.5	LSB
Absolute accuracy	—	—	TBD	—	—	TBD	LSB